

# Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

## **Quality Overview**

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
  - Class Q Military
  - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.



April 1988 Revised October 2000

# 74F823 9-Bit D-Type Flip-Flop

#### **General Description**

# The 74F823 is a 9-bit buffered register. It features Clock Enable and Clear which are ideal for parity bus interfacing in high performance microprogramming systems.

#### **Features**

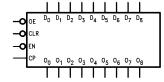
- 3-STATE outputs
- Clock Enable and Clear

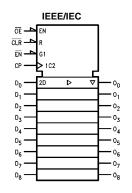
### **Ordering Code:**

Order Number	Package Number	Package Description
74F823SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F823SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

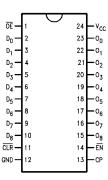
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Logic Symbols**





## **Connection Diagram**



#### **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>
D <sub>0</sub> -D <sub>8</sub> OE	Data Inputs	1.0/1.0	20 μA/–0.6 mA
OE	Output Enable Input	1.0/1.0	20 μA/-0.6 mA
CLR	Clear	1.0/1.0	20 μA/–0.6 mA
CP	Clock Input	1.0/2.0	20 μA/–1.2 mA
EN	Clock Enable	1.0/1.0	20 μA/–0.6 mA
O <sub>0</sub> -O <sub>8</sub>	3-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)

### **Functional Description**

The 74F823 device consists of nine D-type edge-triggered flip-flops. It has 3-STATE true outputs and is organized in broadside pinning. The buffered Clock (CP) and buffered Output Enable (OE) are common to all flip-flops. The flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH CP transition. With the OE LOW the contents of the flip-flops are available at the outputs. When the OE is HIGH, the outputs go to the high impedance state. Operation of the OE input does not affect the state of the flip-flops. In addition to the Clock and Output Enable pins, the 74F823 has Clear ( $\overline{\text{CLR}}$ ) and Clock Enable ( $\overline{\text{EN}}$ ) pins.

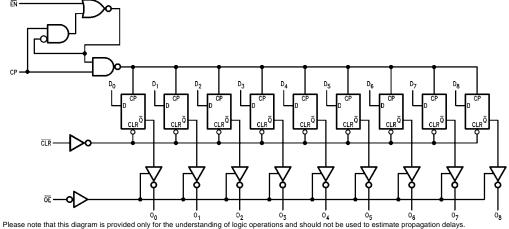
When the  $\overline{\text{CLR}}$  is LOW and the  $\overline{\text{OE}}$  is LOW, the outputs are LOW. When CLR is HIGH, data can be entered into the flip-flops. When EN is LOW, data on the inputs is transferred to the outputs on the LOW-to-HIGH clock transition. When the EN is HIGH, the outputs do not change state regardless of the data or clock inputs transitions. This device is ideal for parity bus interfacing in high performance systems.

#### **Function Table**

	Inp	outs			Internal	Output	Function
ΟE	CLR	EN	СР	D	Q	0	runction
Н	Н	L	Н	Χ	NC	Z	Hold
Н	Н	L	L	Χ	NC	Z	Hold
Н	Н	Н	Χ	Χ	NC	Z	Hold
L	Н	Н	Χ	Χ	NC	NC	Hold
Н	L	Χ	Χ	Χ	Н	Z	Clear
L	L	Χ	Χ	Χ	Н	L	Clear
Н	Н	L	_	Н	Н	Z	Load
Н	Н	L	_	Н	L	Z	Load
L	Н	L	_	L	Н	L	Data Available
L	Н	L	~	Н	L	Н	Data Available
L	Н	L	Н	Χ	NC	NC	No Change in Data
L	Н	L	L	Χ	NC	NC	No Change in Data

- L = LOW Voltage Level
- H = HIGH Voltage Level
- X = Immaterial
- Z = High Impedance
- = LOW-to-HIGH Transition
- NC = No Change

#### **Logic Diagram**



#### **Absolute Maximum Ratings**(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

#### **Recommended Operating Conditions**

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

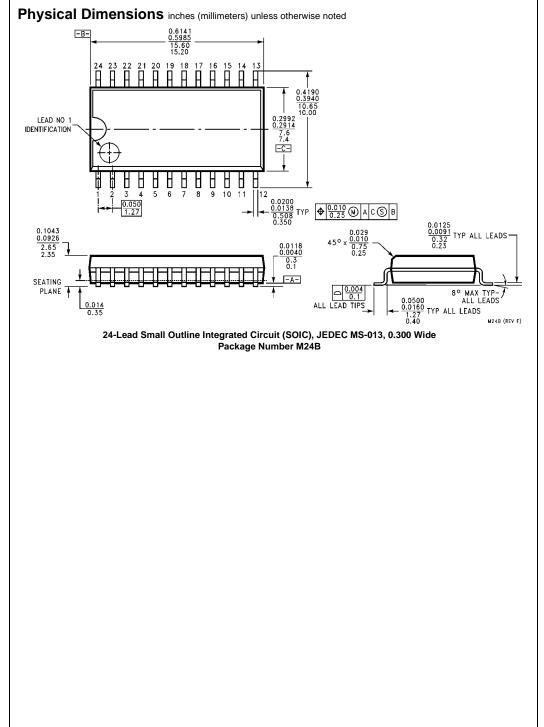
Symbol	Parameter		Min	Тур	Max	Units	v <sub>cc</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage				8.0	V		Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA	
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5					I <sub>OH</sub> = -1 mA	
	Voltage	10% V <sub>CC</sub>	2.4			V	Min	$I_{OH} = -3 \text{ mA}$	
		5% V <sub>CC</sub>	2.7			V	IVIII	$I_{OH} = -1 \text{ mA}$	
		5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA}$	
V <sub>OL</sub>	Output LOW Voltage	10% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 24 mA	
I <sub>IH</sub>	Input HIGH				5.0	^	Max	\/ 2.7\/	
	Current				5.0	μА	IVIAX	V <sub>IN</sub> = 2.7V	
I <sub>BVI</sub>	Input HIGH Current				7.0		Max	\/ -70\/	
	Breakdown Test				7.0	μА	IVIAX	V <sub>IN</sub> = 7.0V	
I <sub>CEX</sub>	Output HIGH				50	^	Max	V V	
	Leakage Current				50	μА	IVIAX	$V_{OUT} = V_{CC}$	
V <sub>ID</sub>	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test		4.75			V	0.0	All Other Pins Grounded	
I <sub>OD</sub>	Output Leakage				3.75		0.0	V <sub>IOD</sub> = 150 mV	
	Circuit Current				3.75	μА	0.0	All Other Pins Grounded	
Ι <sub>ΙL</sub>	Input LOW				-0.6	mA	Max	V <sub>IN</sub> = 0.5V (OE, CLR, EN)	
	Current				-1.2	mA	Max	V <sub>IN</sub> = 0.5V (CP)	
l <sub>OZH</sub>	Output Leakage Current				50	μА	Max	V <sub>OUT</sub> = 2.7V	
l <sub>OZL</sub>	Output Leakage Current				-50	μА	Max	V <sub>OUT</sub> = 0.5V	
los	Output Short-Circuit Curren	:	-60		-150	mA	Max	V <sub>OUT</sub> = 0V	
I <sub>ZZ</sub>	Buss Drainage Test				500	μΑ	0.0V	V <sub>OUT</sub> = 5.25V	
I <sub>CCZ</sub>	Power Supply Current			75	100	mA	Max	$V_{O} = HIGH Z$	

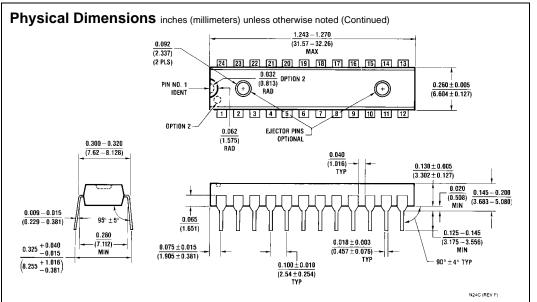
# **AC Electrical Characteristics**

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -55^{\circ}V \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>MAX</sub>	Maximum Clock Frequency	100	160		60		70		MHz
t <sub>PLH</sub>	Propagation Delay	2.0	5.6	9.5	2.0	10.5	2.0	10.5	
t <sub>PHL</sub>	CP to O <sub>n</sub>	2.0	5.2	9.5	2.0	10.5	2.0	10.5	ns
t <sub>PHL</sub>	Propagation Delay  CLR to O <sub>n</sub>	4.0	7.1	12.0	4.0	13.0	4.0	13.0	ns
t <sub>PZH</sub>	Output Enable Time	2.0	5.8	10.5	2.0	13.0	2.0	11.5	
t <sub>PZL</sub>	OE to O <sub>n</sub>	2.0	5.5	10.5	2.0	13.0	2.0	11.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.5	2.9	7.0	1.0	7.5	1.5	7.5	115
t <sub>PLZ</sub>	OE to O <sub>n</sub>	1.5	2.7	7.0	1.0	7.5	1.5	7.5	

# **AC Operating Requirements**

		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = -55^{\circ}V \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
Symbol	Parameter							
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	2.5		4.0		3.0		
t <sub>S</sub> (L)	D <sub>n</sub> to CP	2.5		4.0		3.0		ns
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	2.5		2.5		2.5		115
t <sub>H</sub> (L)	D <sub>n</sub> to CP	2.5		2.5		2.5		
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	4.5		5.0		5.0		
t <sub>S</sub> (L)	EN to CP	2.5		3.0		3.0		ns
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	2.0		3.0		2.0		115
t <sub>H</sub> (L)	EN to CP	0		1.0		0		
t <sub>W</sub> (H)	CP Pulse Width	5.0		6.0		6.0		ns
t <sub>W</sub> (L)	HIGH or LOW	5.0		6.0		6.0		115
t <sub>W</sub> (L)	CLR Pulse Width, LOW	5.0		5.0		5.0		ns
t <sub>REC</sub>	CLR Recovery Time	5.0		5.0		5.0		ns





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N24C

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